

## IN THE CLAIMS

1. (Currently Amended) A ~~computerized~~ method for generating a testbench, the ~~method~~ comprising:

generating a plurality of test designs, the plurality of test designs having varied characteristics to allow testing of a design automation tool, wherein generating one of the plurality of test designs comprises:

instantiating the I/O structure of a top level module, the top level module having input and output pins;

selecting a plurality of submodules from a design module library, wherein cost constraints are used to select the plurality of submodules;

parameterizing ~~the a-~~plurality of submodules from ~~the a-~~design module library for interconnection with the top level module, the plurality of submodules having input and output lines;

providing logic to interconnect the plurality of parameterized submodules as well as to connect the plurality of parameterized submodules to various input and output pins of the top level module; -

applying the plurality of test designs to test the design automation tool.

2. (Currently Amended) The ~~computerized~~ method of claim 1, wherein the design automation tool is used to implement hardware descriptor language designs on a programmable chip.

3. (Currently Amended) The ~~computerized~~ method of claim 1, wherein the design automation tool is used to implement designs on an ASIC.

4. (Currently Amended) The ~~computerized~~ method of claim 1, wherein instantiation constraints are used to select the plurality of submodules, the design automation tool is an electronic design automation tool.

5. (Currently Amended) The ~~computerized~~ method of claim 1, wherein the design automation tool is a synthesis or a place and route tool.

6. (Currently Amended) The ~~computerized~~ method of claim 1, wherein providing logic to interconnect the plurality of parameterized modules comprises identifying inputs and outputs.

7. (Currently Amended) The ~~computerized~~ method of claim 6, wherein inputs comprise input pins of the top level module, submodule output lines, and registers.

8. (Currently Amended) The ~~computerized~~—method of claim 6, wherein outputs comprise output pins of the top level module, submodule input lines, and registers.

9. (Currently Amended) The ~~computerized~~—method of claim 8, wherein providing logic to interconnect the plurality of parameterized modules further comprises classifying inputs and outputs as clock lines, control lines, and data lines.

10. (Currently Amended) The ~~computerized~~—method of claim 8, wherein generating one of the plurality of test designs further comprises:

generating randomized logic.

11. (Currently Amended) The ~~computerized~~—method of claim 10, wherein randomized logic is generated to drive outputs.

12. (Currently Amended) The ~~computerized~~—method of claim 10, wherein generating randomized logic comprises directly wiring outputs to inputs, generating a logic expression using inputs, generating a mathematical expression using inputs, or generating decision logic.

13. (Currently Amended) The ~~computerized~~—method of claim 6, wherein parameterizing the plurality of submodules comprises defining interfaces, data width, and the type of signal for input and output lines associated with the submodule.

14. (Currently Amended) The ~~computerized~~—method of claim 6, wherein submodules comprise adders, phase lock loops, memory, and timers.

15. (Currently Amended) The ~~computerized~~—method of claim 6, wherein generating one of the plurality of test design further comprises selecting a clock structure for each output.

16. (Currently Amended) The ~~computerized~~—method of claim 15, wherein clock structures include a plurality of synchronous and asynchronous structures.

17. (Currently Amended) A computer system—~~for generating a testbench, the computer system comprising:~~

memory operable to hold information associated with a design module library;

a processor coupled to memory, the processor configured to generate a plurality of test designs, the plurality of test designs having varied characteristics to allow testing of a design automation tool, wherein generating one of the plurality of test designs comprises:

instantiating the I/O structure of a top level module, the top level module having input and output pins;

selecting a plurality of submodules from a design module library, wherein cost constraints are used to select the plurality of submodules;

parameterizing the a-plurality of submodules from the a-design module library for interconnection with the top level module, the plurality of submodules having input and output lines;

providing logic to interconnect the plurality of parameterized submodules as well as to connect the plurality of parameterized submodules to various input and output pins of the top level module;  
applying the plurality of test designs to test the design automation tool.

18. (Original) The computer system of claim 17, wherein the design automation tool is used to implement hardware descriptor language designs on a programmable chip.

19. (Original) The computer system of claim 17, wherein the design automation tool is used to implement designs on an ASIC.

20. (Original) The computer system of claim 17, wherein the design automation tool is an electronic design automation tool.

21. (Original) The computer system of claim 17, wherein the design automation tool is a synthesis or a place and route tool.

22. (Original) The computer system of claim 17, wherein providing logic to interconnect the plurality of parameterized modules comprises identifying inputs and outputs.

23. (Original) The computer system of claim 22, wherein inputs comprise input pins of the top level module, submodule output lines, and registers.

24. (Original) The computer system of claim 22, wherein outputs comprise output pins of the top level module, submodule input lines, and registers.

25. (Currently Amended) An apparatus for generating test a testbench, the apparatus comprising:

means for generating a plurality of test designs, the plurality of test designs having varied characteristics to allow testing of a design automation tool, wherein means for generating one of the plurality of test designs comprises:

means for instantiating the I/O structure of a top level module, the top level module having input and output pins;

means for selecting a plurality of submodules from a design module library,  
wherein cost constraints are used to select the plurality of submodules;

means for parameterizing the a-plurality of submodules from the a-design module library for interconnection with the top level module, the plurality of submodules having input and output lines;

means for providing logic to interconnect the plurality of parameterized submodules as well as to connect the plurality of parameterized submodules to various input and output pins of the top level module; -

means for applying the plurality of test designs to test the design automation tool.

26. (Currently Amended) The ~~apparatus or computerized method~~ of claim 25, wherein the design automation tool is used to implement hardware descriptor language designs on a programmable chip.

27. (Currently Amended) The ~~apparatus or computerized method~~ of claim 25, wherein the design automation tool is used to implement designs on an ASIC.